

**Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

1 (currently amended). A probe station for testing a device under test comprising:

- (a) a first platen supporting an electrical probe;
- (b) a chuck supporting said device under test;
- (c) a second platen supporting an optical probe;
- (d) said first platen positioned above said device under test and said second platen positioned above said device under test;
- (e) at least 70% of the top surface of said second platen terminating in free space when said optical probe is not supported thereon.

2 (original). The probe station of claim 1 wherein at least 80% of the top surface of said second platen terminating in free space when said optical probe is not supported thereon.

3 (currently amended). The probe station of claim 1 wherein ~~at least 80% of the top surface of said second platen terminating in free space when said optical probe is not supported thereon~~ said first and second platen are capable of relevant movement with respect to one another.

4 (original). The probe station of claim 1 wherein at least 85% of the top surface of said second platen terminating in free space when said optical probe is not supported thereon.

5 (original). The probe station of claim 1 wherein at least 90% of the top surface of said second platen terminating in free space when said optical probe is not supported thereon.

6 (original). The probe station of claim 1 wherein at least 95% of the top surface of said second platen terminating in free space when said optical probe is not supported thereon.

7 (original). The probe station of claim 1 wherein said second platen has a greater top surface area than said first platen.

8 (original). The probe station of claim 1 wherein said second platen has a smaller top surface area than said first platen.

~~8-9~~ (currently amended). The probe station of claim 1 wherein said second platen has the same surface area as said first platen.

10 (original). The probe station of claim 1 wherein said first platen is maintained in position with respect to said second platen by gravity such that if said probe station were turned upside down said first platen would freely fall away from said second platen.